## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination LIN, SHIN-SENG Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,331,213	05-1982	Taniguchi, Yoshifumi	181/263
*	В	US-6,554,100	04-2003	Kim, Young Tae	181/279
*	C	US-6,385,967	05-2002	Chen, Shun-Lai	60/312
*	D	US-4,667,770	05-1987	DeVane, Harry M.	181/280
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	. 1	US-			
	J	US-			
	К	US-			
	L.	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.